

**Search Notes****Application/Control No.**

10/534,134

**Examiner**

Sang Y. Paik

**Applicant(s)/Patent under Reexamination**

JEONG ET AL.

**Art Unit**

3742

**SEARCHED**

Class	Subclass	Date	Examiner
392	386		
	387		
	388		
	389		
118	726		
420	192		
	193		
	113		
428	401		
	216	4/27/06	SP

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EXAMINER REFERRED	4/27/06	SP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner